

Notice of References Cited	Application/Control No. 10/043,486	Applicant(s)/Patent Under Reexamination MOTIKA ET AL.	
	Examiner John P Trimmings	Art Unit 2133	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
<input checked="" type="checkbox"/>	A	US-5,303,246	04-1994	Anderson et al.	714/727
<input type="checkbox"/>	B	US-			
<input type="checkbox"/>	C	US-			
<input type="checkbox"/>	D	US-			
<input type="checkbox"/>	E	US-			
<input type="checkbox"/>	F	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
<input type="checkbox"/>	N					
<input type="checkbox"/>	O					
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<input type="checkbox"/>	R					
<input type="checkbox"/>	S					
<input type="checkbox"/>	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
<input type="checkbox"/>	U	"A Technique for Fault Diagnosis of Defects in Scan Chains", Guo et al., Int'l Test Conference Proceedings 2001, 30 Oct. - 1 Nov. 2001, pp 268-277.
<input type="checkbox"/>	V	"Fast Technique for Locating Faults in Shift Register Latches", IBM Technical Bulletin NN7906229, June, 1979.
<input type="checkbox"/>	W	"Combined Multi Corner Testing with Time and or Voltage Modulation", IBM Technical Bulletin NN81081677, August 1981.
<input type="checkbox"/>	X	"Measurement of Power Bus Noise Sensitivity of VLSI Circuits with Automated Functional Tester", IBM Technical Disclosure NN9201226.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.